

A Probe of the Color Force

On Behalf of the E06014 Collaboration

Hall A Collaboration Meeting 09 December 2010

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Thursday, December 9, 2010

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<u>OUTLINE</u>

- What d_2^n is
- Experimental Set-Up
- LHRS
- BigBite
- Optics
- MWDC
- Cherenkov





 d_2^n gives access to quark-gluon correlations

$$d_2^n = \int_0^1 x^2 [2g_1^n(x, Q^2) + 3g_2^n(x, Q^2)] dx$$

• How do we interpret d_2^n ?

• Average transverse force on a quark just after interaction with a virtual photon (M. Burkardt)



Target Polarization





LHRS: Pion Rejector



LHRS: Cherenkov



BigBite Negative Optics



I-Pass Carbon

Majority of optics done by Xin during Transversity

Vertex resolution at centimeter level



BigBite Negative Optics



BigBite MWDC

u1 Plane u1p Plane u2 Plane 2000 12000 10000 0000 10000 8000 8000 8000 6000 6000 6000 4000 4000 4000 2000 2000 2000 σ = 0.25555 mm σ = 0.25566 mm $\sigma = 0.25302 \text{ mm}$ -0.001 -0.001 -0.001 -0.0005 0.0005 -0.0005 0.0005 0.001 -0.0005 0.0005 0.001 0 0.001 0 0 Track Residual (m) Track Residual (m) Track Residual (m) u2p Plane u3 Plane u3p Plane 16000 16000 2000 14000 14000 10000 12000 12000 8000 10000 10000 6000 8000 8000 6000 6000 4000 4000 4000 2000 2000 2000 σ = 0.24984 mm σ = 0.23699 mr σ = 0.23437 m -0.001 -0.001 -0.001 -0.0005 0.0005 -0.0005 0.0005 -0.0005 0 0.001 0 0.001 0 0.0005 0.001 Track Residual (m) Track Residual (m) Track Residual (m)

U plane track residuals

After calibrating all
MWDC planes the track
residuals are checked

Track residual resolutions varied from 190-265 um

BigBite Shower



BigBite Cherenkov



BigBite Cherenkov: Pion Rejection



 $N_{cer} = Number of pions left after Cherenkov cut$

N
$$_{\pi}~$$
 = Number of events in pion sample

BigBite Cherenkov: Pion Rejection



Small angle side pion rejection factor at 3 photo-electron cut ~200

Large angle side pion rejection factor at 3 photo-electron cut ~900



• N_e = number of events in electron sample

 N_{cer} = number of events in electron sample after Cherenkov cut

PMTs on small-angle (beamline) side



Small angle average electron detection efficiency >85%

PMTs on the large-angle (RHRS) side



Large angle average electron detection efficiency >90%



- Studying LHRS acceptance
- Finalize Cherenkov pion rejection factors and electron efficiencies
- Fine tune shower calibrations
- Data quality checks
- Begin extracting asymmetries



- 👱 B. Sawatzky, Z.-E. Meziani, G. Franklin, L. El Fassi
- P. H. Solvignon, V. Sulkosky, S. Riordan, Yi Zhang
- X. Qian, J. Huang, K. Allada, C. Dutta, Yawei Zhang
- D. Flay, D. Parno
- The E06014 Collaboration



BigBite MWDC

t0 calibration





t0 calibration was done for each plane

t0 calibrated to within 10 ns

drift distance to drift time



Drift distance to drift time was parameterized for each plane

T2 Trigger

			Sh/PSh Sum#	Short patch cable	Long patch cable
		A	26	N4-24L	20
	-	В	25	N2-24L	24
		>c	24	N3-21L	52
CI	C1 overlaps with A+B+C+D	D	23	N6-36L	-
		 E	22	N3-22L	6
/		F	21	N4-21L	17
C2	C2 overlaps with D+E+F+G	G	20	N4-23L	-
		н	19	N1-21L	S6–1NAU
C3	C3 overlaps with G+H+I+J	Ι	18	N1-22L	23
		J	17	N3-24L	-
C4	C4 overlaps with J+K+L+M	K	16	N2-21L	2
		L	15	N2-22L	14
C5 C6	C5 overlaps with M+N+O+P C6 overlaps with P+Q+R+S	M	14	N1-24L	-
		N	13	N4-22L	51
		0	12	N2-23L	11
		Р	11	N3-23L	-
		Q	10	N7-32L	1
C7	C7 overlaps with S+T+U+V	R	9	N5-32L	9
		S	8	N1-23L	-
C8 C9	C9 overlaps with Y+Z	Т	7	N6-33L	53
		U	6	N6-31L	5
		- V	5	N5-36L	-
		W	4	N7-33L	3
		X	3	N6-32L	21
		Y	2	N6-35L	-
		Z	1	N5-31L	50